

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/623,556	SHIRAISHI, KENJI	
Examiner	Art Unit	
Nhan T. Tran	2622	

	SEARCHED		
Class	Subclass	Date	Examiner

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
PGPUB text search - see search history printout		10/29/2007	NT		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Updated EAST search (USPAT, JPO, EPO, DERWENT, IBM_TDB)	10/4/2007	NT		
Text search classes 348, 358, 386 and 382 - see search history printout	10/28/2007	NT		
Text search all classes - see search history printout	10/28/2007	NT		
Inventorship search - see search history printout	10/29/2007	NT		